

<b>Notice of References Cited</b>	Application/Control No. 10/692,739	Applicant(s)/Patent Under Reexamination CHANG, LIANG-JEN	
	Examiner Evan H Langdon	Art Unit 3654	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0056776 A1	05-2002	Sugawara, Ken?	242/231
	B	US-2003/0146325 A1	08-2003	Kitajima, Keigo	242/311
	C	US-6,629,655 B2	10-2003	Kitajima, Keigo	242/311
	D	US-3,877,658	04-1975	Lemery, Jean Paul	242/236
	E	US-5,540,397	07-1996	Yoshikawa, Osamu	242/311
	F	US-D460,516	07-2002	Yoshikawa et al.	D22/141
	G	US-D487,496	03-2004	Iwabuchi, Masakazu	D22/141
	H	US-D467,299	12-2002	Kondo et al.	D22/141
	I	US-6,138,935	10-2000	Zwayer et al.	242/311
	J	US-6,572,043	06-2003	Burke et al.	242/244
	K	US-D388,497	12-1997	Iwabuchi, Masakazu	D22/141
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.